# Abstracts

## Pulsed Device Measurements and Applications

*J. Scott, J.G. Rathmell, A. Parker and M. Sayed. "Pulsed Device Measurements and Applications." 1996 Transactions on Microwave Theory and Techniques 44.12 (Dec. 1996, Part II [T-MTT] (1996 Symposium Issue)): 2718-2723.*

A pulsed measurement system can provide more than just isothermal characteristic data. An off-the-shelf system can determine rapidly the timing necessary for both pulsed-1-V and pulsed-S-parameter measurements to be isothermal and iso-dynamic. Instantaneous channel temperature may be determined. Thermal and charge-trapping effects can be separated and time constants measured. Full gain-derivative surfaces can be ob-tained far more efficiently than by spectral sweep measurements. Characteristics and transient effects following excursions beyond the safe-operating-area and into breakdown may be observed nondestructively.

❑ Return to main document.